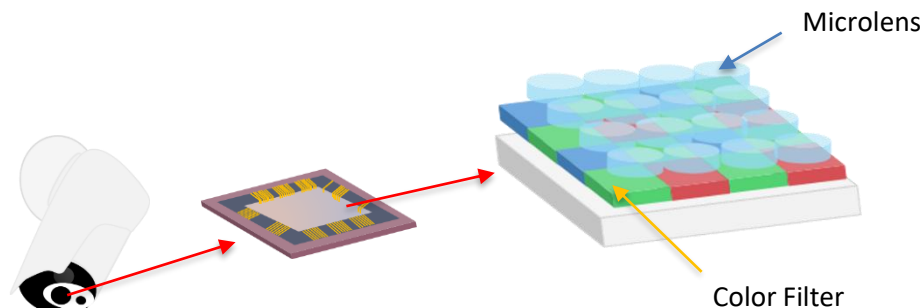


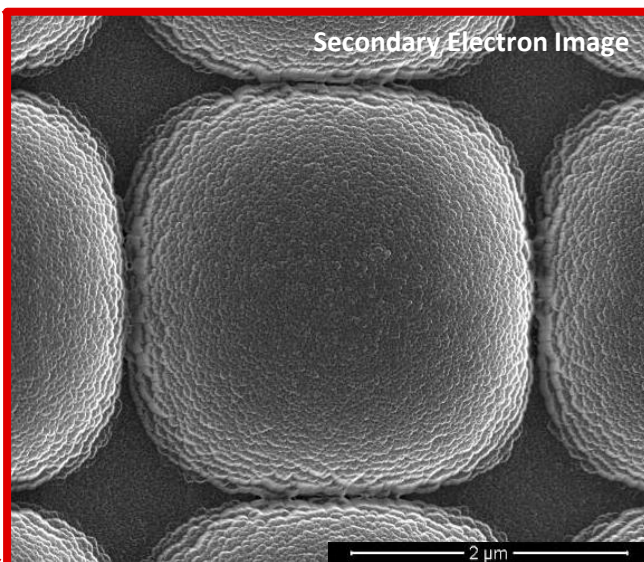
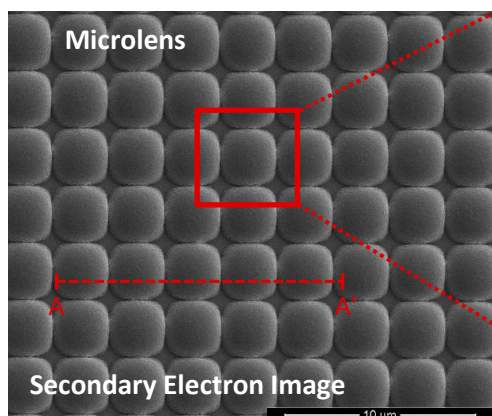
Surface and Cross-Sectional SEM Observation of an Image Sensor

SEM Observation of a CMOS Image Sensor

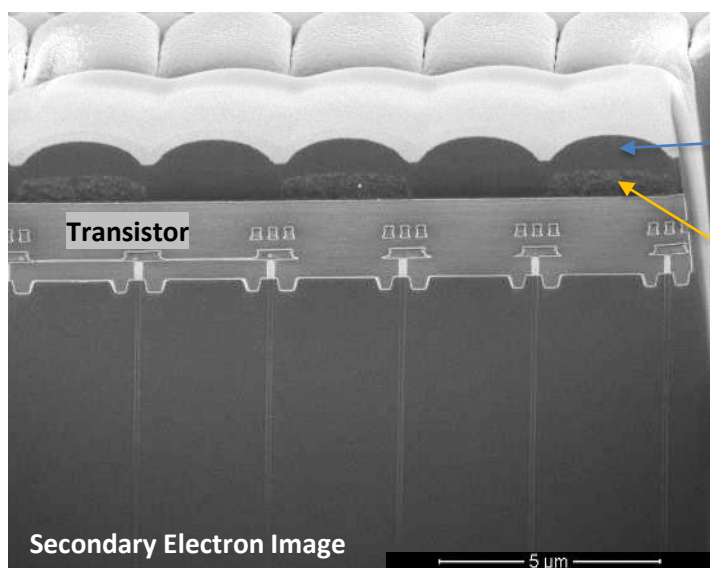
Scanning electron microscopy (SEM) provides high-resolution observation of the morphology of various materials. Below are observations of the surface and cross-sectional structures of a CMOS image sensor removed from a commercial webcam.



<Surface View>



<Cross-Sectional View of A – A'>



The microlenses on the image sensor surface are periodically arranged, and each lens exhibits microscopic surface roughness.

Microlens
Color Filter

In the cross-section of the image sensor, features such as color filters and transistors can be seen beneath the microlenses. The observed structures vary depending on the cross-sectional direction and location.

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